

# Search Notes



Application/Control No.

10/658,015

Examiner

Mathieu D. Vargot

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

1732

## SEARCHED

Class	Subclass	Date	Examiner
264	1-1, 1-7, 1-24		
362	24	7/30/05	MDV

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR